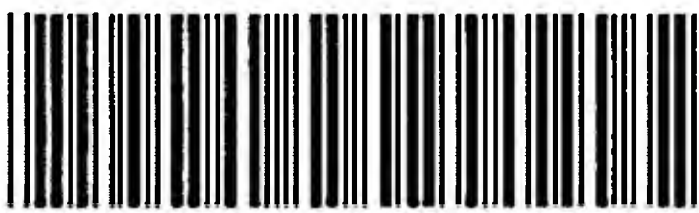


<b>Search Notes</b> 	<b>Application No.</b>	<b>Applicant(s)</b>	
	10/604,895	WU, CHING-HSIU	
	<b>Examiner</b>	<b>Art Unit</b>	
	Stephen W. Smoot	2813	

SEARCHED			
Class	Subclass	Date	Examiner
438	4	8/7/2004	SWS
438	14	8/7/2004	SWS
438	623	8/7/2004	SWS
438	763	8/7/2004	SWS
438	780	8/7/2004	SWS
438	782	8/7/2004	SWS
438	788	8/7/2004	SWS

S.W.S.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Key Words: Spin-on Material - Glass, SOG, Resist, Photoresist, MSQ, HSQ, Silsesquioxane;	8/7/2004	S.W.S. SWS
Clean, Wash, Rinse - Scrub; Interconnect - Wiring, Trace, Line, Conductor, Metal, Copper, Aluminum;	8/7/2004	S.W.S. SWS
Etch - Dry, Wet, BHF, Ashing, Stripping.	8/7/2004	S.W.S. SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	8/7/2004	S.W.S. SWS